Attorney's Docket No.: 03351-009005

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Michael E. Fossey et al.

Art Unit : 2877

Serial No.: 10/601,698

Examiner: Unknown

Filed

: June 24, 2003

Title

: WAFER INSPECTION SYSTEM FOR DISTINGUISHING PITS AND

PARTICLES

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicant submits the references listed on the attached form PTO-1449. A copy of a communication from a foreign patent office in a counterpart application is also enclosed.

Submitted herewith is an English translation of the following foreign language references, or portions thereof:

Desig. ID	Source
AL	Japan 63-143831 A: English Abstract
AM	Japan 63-298035 A: English Abstract
AN	Japan 6-242012 A: English Abstract

This statement is being filed before the receipt of a first Office action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Reg. No. 37,640

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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 03351-009005	Application No. 10/601,698	
by Ar	closure Statement oplicant	Applicant Michael E. Fossey et a	վ.	
(Use several st	eets if necessary)	Filing Date June 24, 2003	Group Art Unit 2877	

U	b 2004 35	U.S. Patent Documents						
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_		AA						
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	Foreig	n Patent Doo	cuments or P	ublished Foreign	Patent A	Application	าร	
Examiner Initial	Desig.	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Trans Yes	slation No
maai	AL	63143831	6/16/1988	Japan	0.000		X	1,0
	AM	63298035	12/5/1988	Japan			Х	
	AN	06242012	9/2/1994	Japan			Х	
	AO	WO96/27786	2/9/1999	WPO				X
	AP							

	Other Documents (include Author, Title, Date, and Place of Publication)					
Examiner	Desig.					
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	AR					
	AS					
	AT					

Examiner Signature	Date Considered		
EXAMINER: Initials citation considered. Draw line through citation if no next communication to applicant.	t in conformance and not considered. Include copy of this form with		